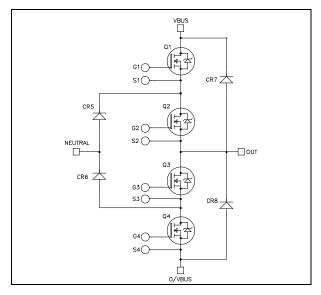
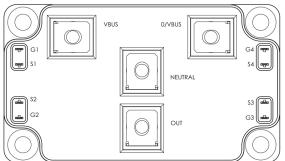


Three level inverter SiC MOSFET Power Module





SiC Power MOSFET:

 $V_{DSS} = 1200V ; R_{DSon} = 13m\Omega @ Tj = 25^{\circ}C$

Application

• Uninterruptible Power Supplies

Features

- SiC Power MOSFET
 - Low R_{DS(on)}
 - High temperature performance

• SiC Schottky Diode

- Zero reverse recovery
- Zero forward recovery
- Temperature Independent switching behavior
- Positive temperature coefficient on VF
- Kelvin emitter for easy drive
- Very low stray inductance
- M5 power connectors
- High level of integration
- AlN substrate for improved thermal performance

Benefits

- Stable temperature behavior
- Very rugged
- Direct mounting to heatsink (isolated package)
- Low junction to case thermal resistance
- Easy paralleling due to positive TC of VCEsat
- Low profile
- RoHS Compliant

All ratings (a) $T_i = 25$ °C unless otherwise specified

Q1 to Q4 Absolute maximum ratings (per SiC MOSFET)

Symbol	Parameter	Max ratings	Unit	
$V_{ m DSS}$	Drain - Source Breakdown Voltage		1200	V
Ţ	Cantinuana David Comment	$T_c = 25^{\circ}C$	215	
I_D	Continuous Drain Current	$T_c = 80^{\circ}C$	160	A
I_{DM}	Pulsed Drain current		440	
V_{GS}	Gate - Source Voltage		-10/+25	V
R_{DSon}	Drain - Source ON Resistance	13	mΩ	
P_D	Maximum Power Dissipation	$T_c = 25^{\circ}C$	1000	W

CAUTION: These Devices are sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed. See application note APT0502 on www.microsemi.com



Q1 to Q4 Electrical Characteristics (per SiC MOSFET)

Symbol	Characteristic	Test Conditions		Min	Тур	Max	Unit
I_{DSS}	Zero Gate Voltage Drain Current	$V_{GS} = 0V$; $V_{DS} = 1200V$			100	800	μΑ
р	Drain – Source on Resistance	$V_{GS} = 20V$	$T_j = 25^{\circ}C$		10	13	
R _{DS(on)}		$I_{\rm D} = 160 A$	$T_j = 150$ °C		19	26	mΩ
$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS} = V_{DS}$, $I_D = 8mA$		1.7	2.2		V
I_{GSS}	Gate – Source Leakage Current	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$				2	μA

Q1 to Q4 Dynamic Characteristics (per SiC MOSFET)

Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit
C _{iss}	Input Capacitance	$V_{GS} = 0V$			7600		
$\frac{C_{\mathrm{oss}}}{C_{\mathrm{rss}}}$	Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 1000V$ f = 1MHz			640 52		pF
Q _g	Total gate Charge				392		
Q _{gs}	Gate – Source Charge	$V_{GS} = 20V$ $V_{Bus} = 800V$	$V_{GS} = 20V$ $V_{D} = 800V$		88		пC
Q _{gd}	Gate – Drain Charge	$I_{\rm D} = 160 A$			144		
$T_{d(on)}$	Turn-on Delay Time	$V_{GS} = -5/+20V$ $V_{Bus} = 800V$			12		
$T_{\rm r}$	Rise Time				14		
T _{d(off)}	Turn-off Delay Time	$I_{\rm D} = 160 A$	$I_D = 160A$		23		ns
T_{f}	Fall Time	$R_L = 5\Omega$; $R_G = 6.2$	δΩ		18		
Eon	Turn on Energy	Inductive Switching $V_{GS} = -5/+20V$ $V_{Bus} = 600V$	$T_j = 150$ °C		3.5		mJ
E _{off}	Turn off Energy	$I_{D} = 160A$ $R_{G} = 6.25\Omega$	$T_j = 150$ °C		2		mJ
R_{thJC}	Junction to Case Thermal Resistance	e				0.13	°C/W

Source - Drain diode ratings and characteristics (per SiC MOSFET)

Symbol	Characteristic	Test Conditions	Min	Тур	Max	Unit
V	Diode Forward Voltage	$V_{GS} = -5V$; $I_F = 80A$		3.3		V
V_{SD}	Diode Forward Voltage	$V_{GS} = -2V; I_F = 80A$		3.1		V
t_{rr}	Reverse Recovery Time	$I_F = 160A$; $V_R = 800V$		40		ns
Q _{rr}	Reverse Recovery Charge	$di_{S}/dt = 2800A/\mu s$; $V_{GS} = -5V$		1.3		μС



CR5 & CR6 SiC diode ratings and characteristics (Per SiC diode)

Symbol	Characteristic	Test Conditions	Min	Тур	Max	Unit	
V_{RRM}	Maximum Peak Repetitive Reverse Voltage			600			V
I_{RM}	Maximum Reverse Leakage Current	$V_p=600V$	$T_j = 25$ °C		220	1320	μA
1 _{RM}	Waximum Reverse Leakage Current		$T_{i} = 175^{\circ}C$	$T_j = 175$ °C		440	6600
I_F	DC Forward Current		Tc = 125°C		220		A
V_{F}	Diode Forward Voltage	$I_F = 220A$ $\frac{T_i = 25^{\circ}C}{T_i = 175^{\circ}C}$	$T_i = 25^{\circ}C$		1.6	1.8	V
v _F	Diode Forward Voltage		$T_i = 175$ °C		2	2.4	v
Qc	Total Capacitive Charge	$\begin{split} I_F &= 220 A, \ V_R = 600 V \\ di/dt &= 5000 A/\mu s \end{split}$			616		nC
C	Total Capacitance	$f = 1 MHz, V_R = 200V$ $f = 1 MHz, V_R = 400V$	200V		1430		ъE
			400V		1100		pF
R_{thJC}	Junction to Case Thermal Resistance					0.1	°C/W

CR7 & CR8 diode ratings and characteristics (Per SiC diode)

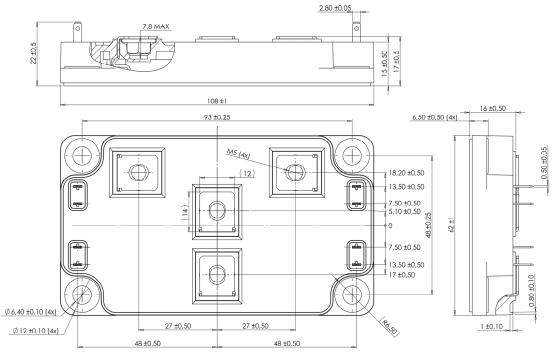
Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit	
V_{RRM}	Maximum Peak Repetitive Reverse Voltage			1200			V	
T	W : P I I	$V_{p}=1200V -$	$T_j = 25^{\circ}C$		280	1600	4	
I_{RM}	Maximum Reverse Leakage Current		V _R =1200V	$V_R=1200V$ $T_j=$	$T_{j} = 175^{\circ}C$		520	3200
I_F	DC Forward Current		Tc = 125°C		160		A	
V_{F}	Diode Forward Voltage	$I_{\rm F} = 160 A$	$T_i = 25^{\circ}C$		1.5	1.8	V	
v F	Diode Forward Voltage	I _F - 100A	$T_{\rm i} = 175^{\circ}$	$T_i = 175^{\circ}C$		2.2	3	V
Qc	Total Capacitive Charge	$I_F = 160A, V_R = 1200V$ di/dt = 1600A/ μ s			1040		nC	
С	Total Capacitance	$f = 1MHz, V_R = 400V$	400V		744		рF	
		$f = 1MHz, V_R =$	800V		536		pr.	
R_{thJC}	Junction to Case Thermal Resistance					0.18	°C/W	

Thermal and package characteristics

Symbol	Characteristic			Min	Тур	Max	Unit
V_{ISOL}	RMS Isolation Voltage, any terminal to c	ase $t = 1 \min_{t \in S} \frac{t}{t}$	50/60Hz	4000			V
т	Operating junction temperature range SiC MOSFET SiC diode		SiC MOSFET	-40		150	
T_{J}			-40		175		
T_{JOP}	Recommended junction temperature under	er switching co	switching conditions			T_J max	°C
1 JOP	Recommended junction temperature under switching conditions			-40		-25	
T_{STG}	Storage Temperature Range			-40		125	
$T_{\rm C}$	Operating Case Temperature					125	
Torque	Mounting torque	To heatsink	M6	3		5	N.m
Torque	For terminals	s M5	2		3.5	IN.III	
Wt	Package Weight					300	g

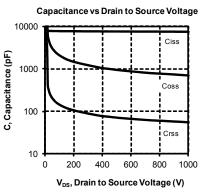


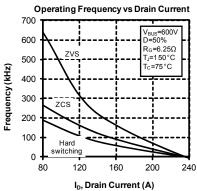
SP6 Package outline (dimensions in mm)

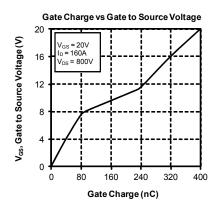


See application note APT0601 - Mounting Instructions for SP6 Power Modules on www.microsemi.com

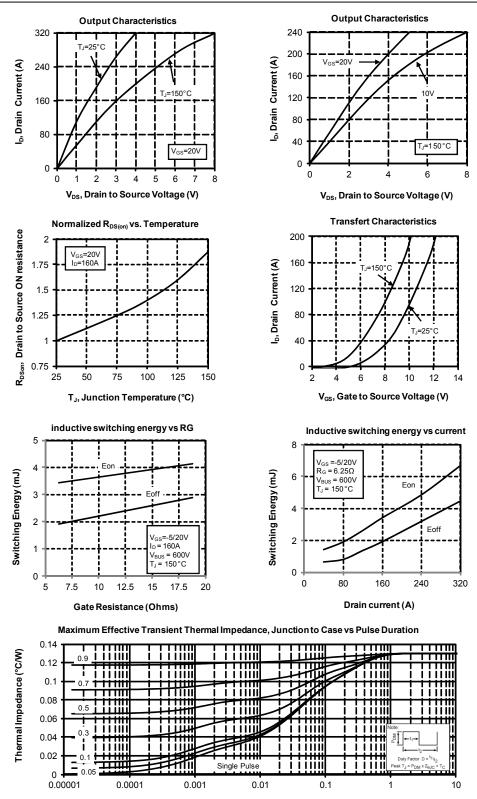
Q1 to Q4 Typical performance curve









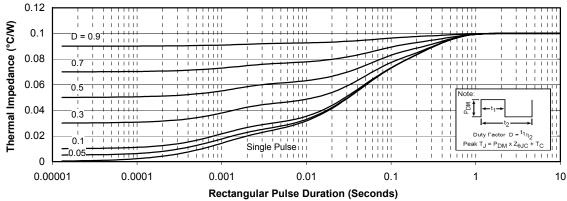


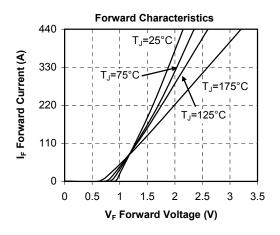
rectangular Pulse Duration (Seconds)

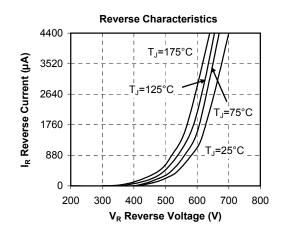


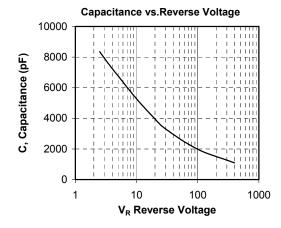
CR5 & CR6 Typical performance curve

Maximum Effective Transient Thermal Impedance, Junction to Case vs Pulse Duration





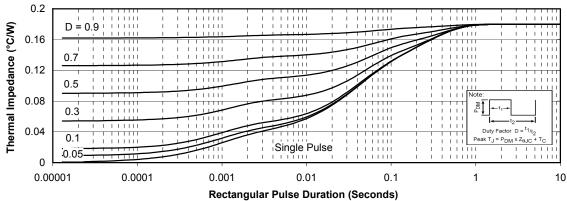


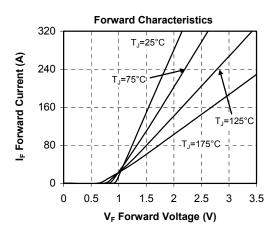


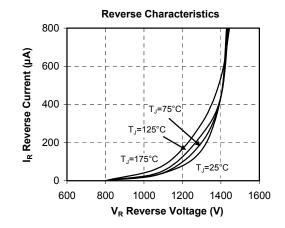


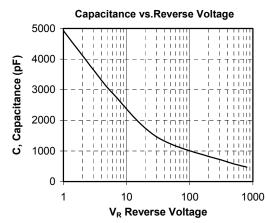
CR7 & CR8 Typical performance curve

Maximum Effective Transient Thermal Impedance, Junction to Case vs Pulse Duration









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